



Power MOSFETS

DATASHEET

LM1CD57NAI8A

N-Channel
Enhancement Mode MOSFET

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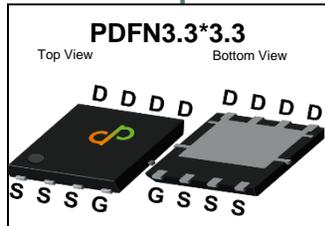


Quality Management Systems

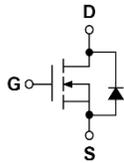
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description



Symbol



Product Summary

Symbol	N-Channel	Unit
V_{DSS}	120	V
$R_{DS(ON)-Max}$	440	m Ω
ID	5.3	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

Applications

- Power Management in DC/DC Converters
- Motor control
- Disconnect switches

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1CD57NAI8A	PDFN3.3*3.3	Tape & Reel	5000 / Tape & Reel	1CD57 □□□□□□

Note : □□□□□□ = Lot Code

Absolute Maximum Ratings ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	120	V
V_{GSS}	Gate-Source Voltage	± 20	V
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$	11.4 A
$I_{DM}^{(1)}$	Pulse Drain Current Tested	$T_C=25^\circ\text{C}$	13.3 A
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	5.3 A
		$T_C=100^\circ\text{C}$	3.4 A
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	12.5 W
		$T_C=100^\circ\text{C}$	5.0 W
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$	1.9 A
		$T_A=70^\circ\text{C}$	1.5 A
P_D	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	1.6 W
		$T_A=70^\circ\text{C}$	1.0 W
$I_{AS}^{(2)}$	Avalanche Current, Single pulse	L=0.1mH	2.5 A
		L=0.5mH	2 A
$E_{AS}^{(2)}$	Avalanche Energy, Single pulse	L=0.1mH	0.3 mJ
		L=0.5mH	1 mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	10 $^\circ\text{C}/\text{W}$
$R_{\theta JA}^{(3)}$	Thermal Resistance-Junction to Ambient	Steady State	80 $^\circ\text{C}/\text{W}$

Note ① : Max. current is limited by junction temperature

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in^2 FR-4 board with 1oz

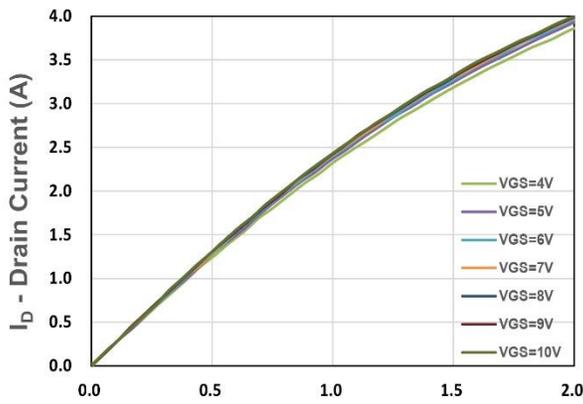
N-Channel Electrical Characteristics (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	120	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	V _{DS} =96V, V _{GS} =0V	-	-	1	uA
V_{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	1	2	3	V
I_{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R_{DS(ON)} ^④	Drain-Source On-state Resistance	V _{GS} =10V, I _{DS} =1A	-	390	440	mΩ
		V _{GS} =4.5V, I _{DS} =0.5A	-	400	495	
g_{fs}	Forward Transconductance	V _{DS} =10V, I _{DS} =0.2A		1	-	S
Dynamic Characteristics ^⑥						
R_G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	4	-	Ω
C_{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =60V, Freq.=1MHz	-	233	-	pF
C_{oss}	Output Capacitance		-	14	-	
C_{rss}	Reverse Transfer Capacitance		-	9	-	
t_{d(ON)}	Turn-on Delay Time	V _{GS} =10V, V _{DS} =25V, I _D =1A, R _{GEN} =1Ω	-	4.3	-	nS
t_r	Turn-on Rise Time		-	2.6	-	
t_{d(OFF)}	Turn-off Delay Time		-	10.9	-	
t_f	Turn-off Fall Time		-	11.7	-	
Q_g	Total Gate Charge	V _{GS} =4.5V, V _{DS} =60V I _D =1A	-	2.5	-	nC
Q_g	Total Gate Charge	V _{GS} =10V, V _{DS} =60V, I _D =1A	-	5.4	-	
Q_{gs}	Gate-Source Charge		-	1.1	-	
Q_{gd}	Gate-Drain Charge		-	0.7	-	
Source-Drain Characteristics						
V_{SD} ^④	Diode Forward Voltage	I _{SD} =0.5A, V _{GS} =0V	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	I _F =1A, V _R =60V	-	20.1	-	nS
Q_{rr}	Reverse Recovery Charge	dI _F /dt=100A/μs	-	14.6	-	nC

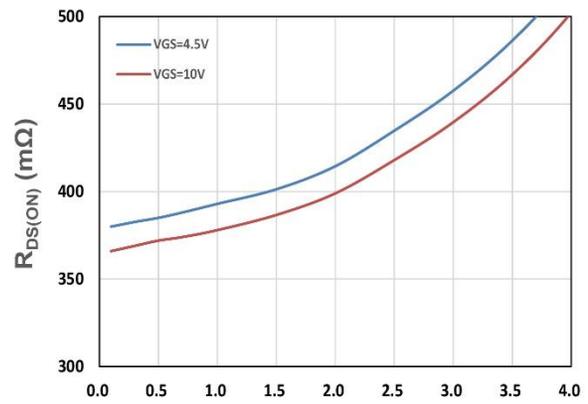
Note ④ : Pulse test (pulse width≤300us, duty cycle≤2%).

Note ⑤ : Guaranteed by design, not subject to production testing.

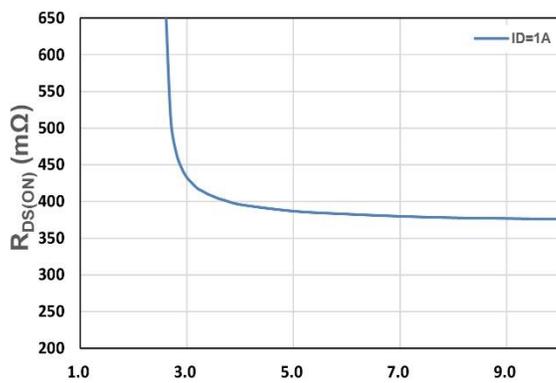
N-Channel Typical Characteristics



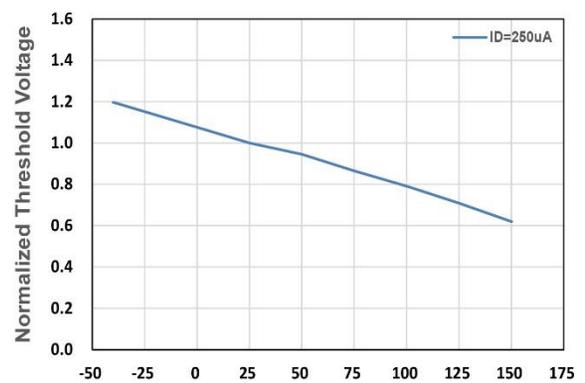
V_{DS} - Drain - Source Voltage (V)
Figure 1. Output Characteristics



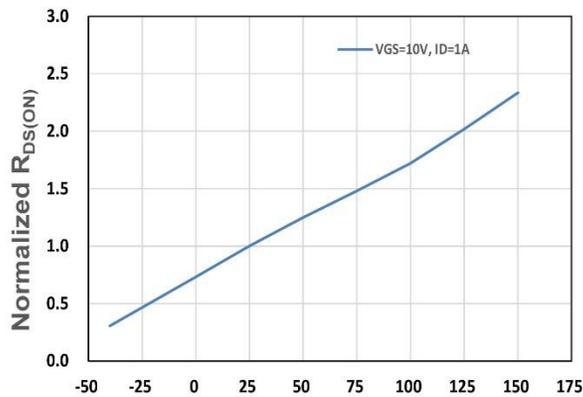
I_D - Drain Current (A)
Figure 2. On-Resistance vs. I_D



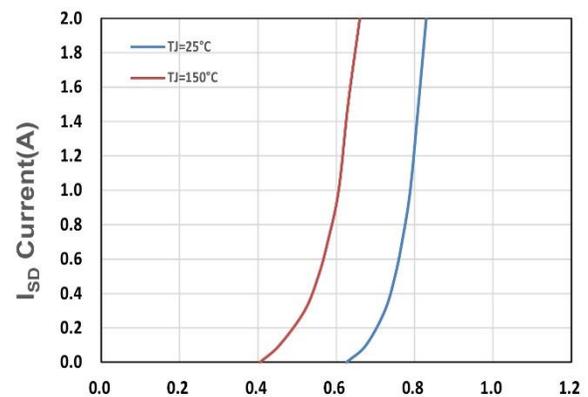
V_{GS} - Gate - Source Voltage (V)
Figure 3. On-Resistance vs. V_{GS}



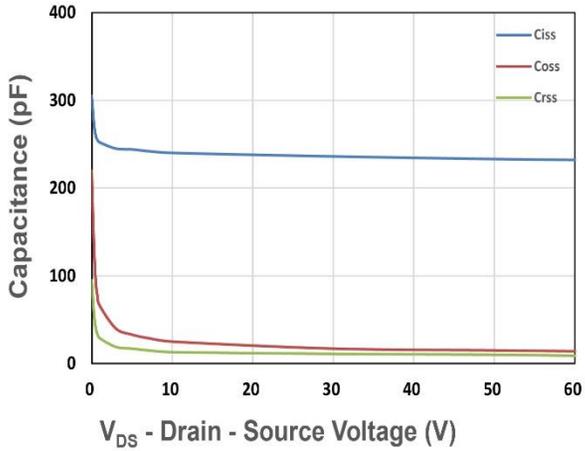
T_j , Junction Temperature($^{\circ}C$)
Figure 4. Gate Threshold Voltage



T_j , Junction Temperature($^{\circ}C$)
Figure 5. Drain-Source On Resistance

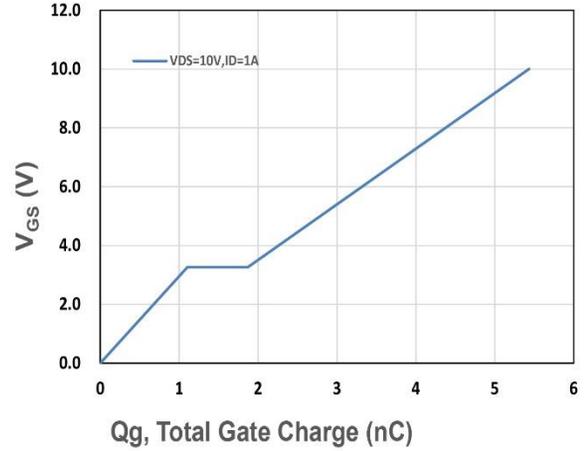


V_{SD} , Source-Drain Voltage(V)
Figure 6. Source-Drain Diode Forward



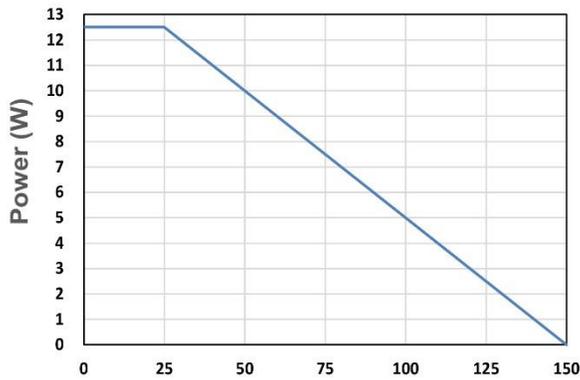
V_{DS} - Drain - Source Voltage (V)

Figure 7. Capacitance



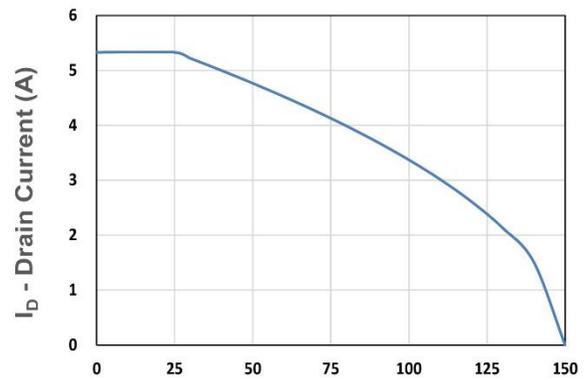
Qg , Total Gate Charge (nC)

Figure 8. Gate Charge Characteristics



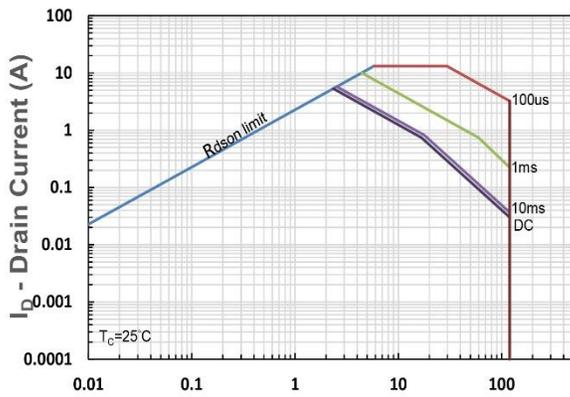
T_C - Case Temperature (°C)

Figure 9. Power Dissipation



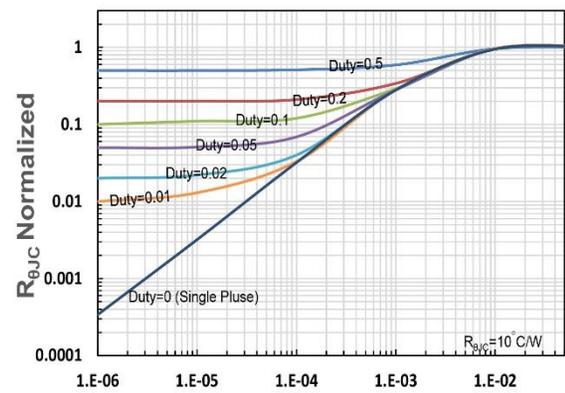
T_C - Case Temperature (°C)

Figure 10. Drain Current



V_{DS} - Drain-Source Voltage (V)

Figure 11. Safe Operating Area



t_1 , Square Wave Pulse Duration(s)

Figure 12. $R_{\theta JC}$ Transient Thermal Impedance